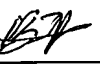

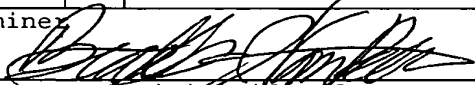


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<u>LIST OF DOCUMENTS CITED BY APPLICANT</u>				Applicant CHIKARAISHI, Kazuo et al.			
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	AG	7-215227	08/15/95	Japan			No
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✓	AO	0 666 210	08/09/95	Europe			
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	AQ						
	AR						
	AS						
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